

MOS FIELD EFFECT TRANSISTOR

2SJ358

P-CHANNEL MOS FET FOR HIGH-SPEED SWITCH

The 2SJ358 is a P-channel vertical MOS FET that can be used as a switching element. The 2SJ358 can be directly driven by an IC operating at 5 V.

The 2SJ358 features a low on-resistance and excellent switching characteristics, and is suitable for applications such as actuator driver and DC/DC converter.

FEATURES

- New-type compact package
Has advantages of packages for small signals and for power transistors, and compensates those disadvantages
- Can be directly driven by an IC operating at 5 V.
- Low on-resistance
 $R_{DS(ON)} = 0.40 \Omega \text{ MAX. @ } V_{GS} = -4 \text{ V, } I_D = -1.5 \text{ A}$
 $R_{DS(ON)} = 0.30 \Omega \text{ MAX. @ } V_{GS} = -10 \text{ V, } I_D = -1.5 \text{ A}$

QUALITY GRADE

Standard

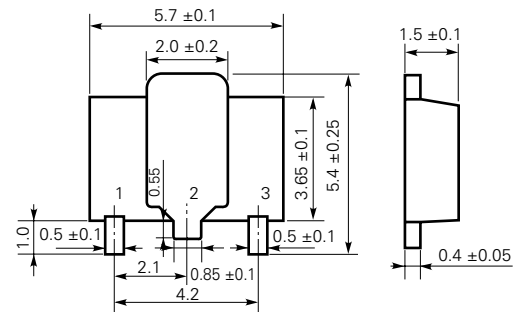
Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS ($T_a = +25 \text{ }^\circ\text{C}$)

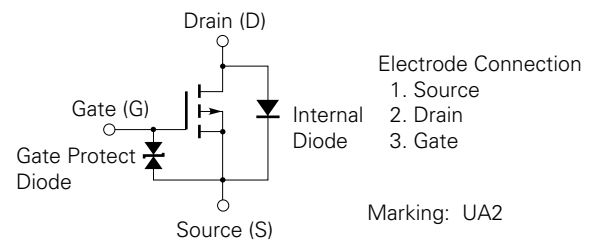
Parameter	Symbol	Conditions	Ratings	Unit
Drain-Source Voltage	V_{DSS}	$V_{GS} = 0$	-60	V
Gate-Source Voltage	V_{GSS}	$V_{DS} = 0$	-20/+10	V
Drain Current (DC)	$I_{D(DC)}$		-/+3.0	A
Drain Current (Pulse)	$I_{D(pulse)}$	$PW \leq 10 \text{ ms}$ Duty Cycle $\leq 1 \%$	-/+6.0	A
Total Power Loss	P_T	Mounted on ceramic board of $7.5 \text{ cm}^2 \times 0.7 \text{ mm}$	2.0	W
Channel Temperature	T_{ch}		150	$^\circ\text{C}$
Storage Temperature	T_{stg}		-55 to +150	$^\circ\text{C}$

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device is actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

Package Drawings (unit: mm)



Equivalent Circuit

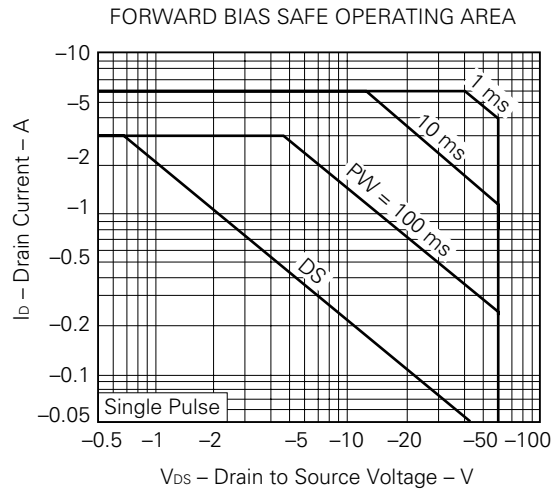
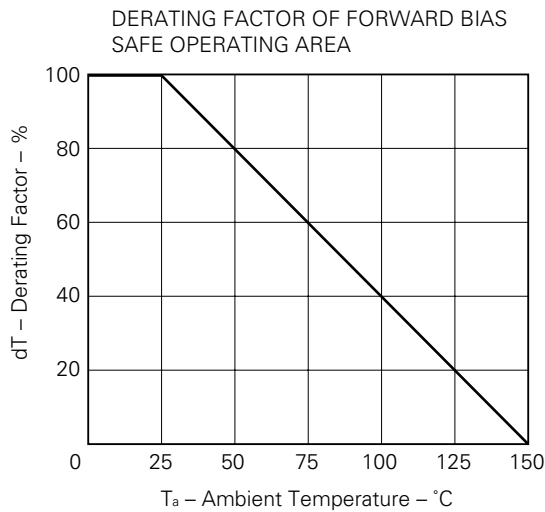


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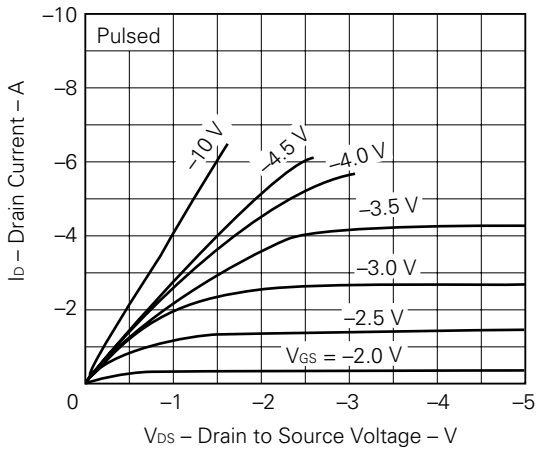
ELECTRICAL SPECIFICATIONS (T_a = +25 °C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Drain Shut-down Current	I _{DSS}	V _{DS} = -60 V, V _{GS} = 0			-10	μA
Gate Leak Current	I _{GSS}	V _{GS} = -16/+10 V, V _{DS} = 0			-/+10	μA
Gate Cutoff Voltage	V _{GS(off)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.4	-2.0	V
Forward Transfer Admittance	Y _{fs1}	V _{DS} = -10 V, I _D = -1.0 A	1.8			S
Drain-Source On-Resistance	R _{DS(on)1}	V _{GS} = -4 V, I _D = -1.5 A		0.29	0.40	Ω
Drain-Source On-Resistance	R _{DS(on)2}	V _{GS} = -10 V, I _D = -1.5 A		0.18	0.30	Ω
Input Capacitance	C _{iss}	V _{DS} = -10 V, V _{GS} = 0,		600		pF
Output Capacitance	C _{oss}	f = 1.0 MHz		300		pF
Feedback Capacitance	C _{rss}			120		pF
On-Time Delay	t _{d(on)}	V _{DD} = -25 V, I _D = -1.5 A		6		ns
Rise Time	t _r	V _{GS(on)} = -10 V		35		ns
Off-Time Delay	t _{d(off)}	R _G = 10 Ω, R _L = 17 Ω		155		ns
Fall Time	t _f			95		ns
Gate Input Charge	Q _G	V _{DS} = -48 V,		23.9		nC
Gate-Source Charge	Q _{GS}	V _{GS} = -10 V,		1.5		nC
Gate-Drain Charge	Q _{GD}	I _D = -3.1 A, I _G = -2 mA		8.1		nC
Internal Diode Reverse Recovery Time	t _{rr}	I _F = 3.0 A di/dt = 50 A/μs		95		ns
Internal Diode Reverse Recovery Charge	Q _{rr}			118		nC

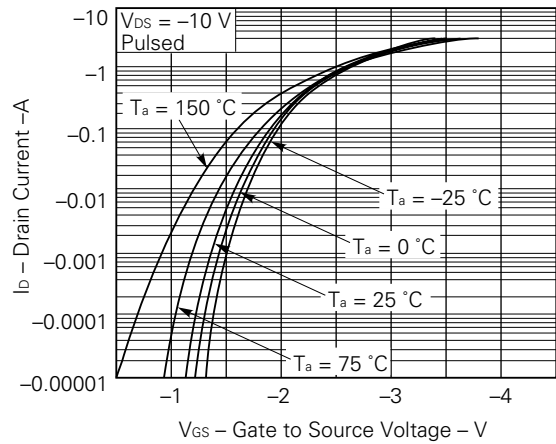
CHARACTERISTICS CURVES (T_a = +25 °C)



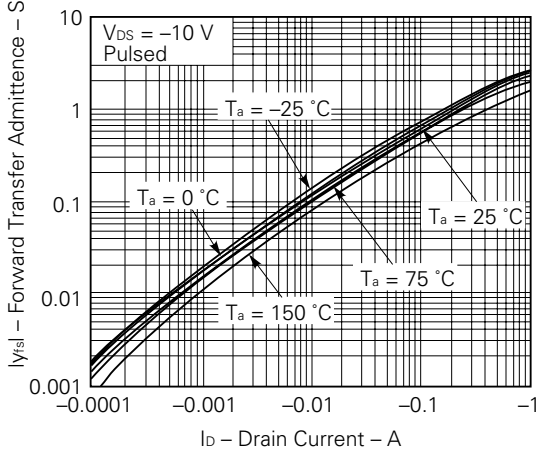
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



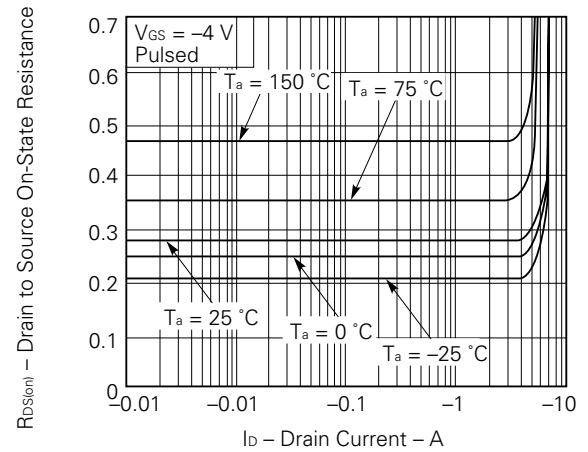
TRANSFER CHARACTERISTICS



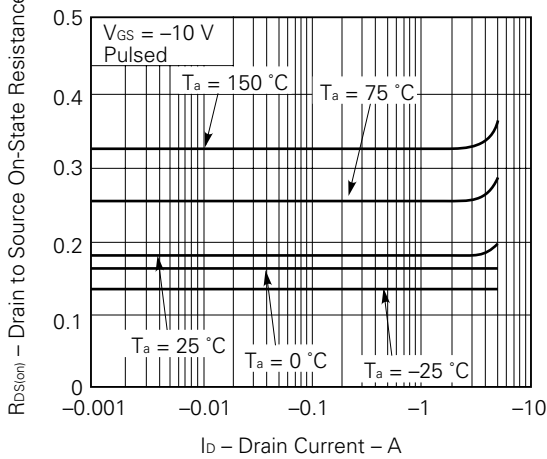
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



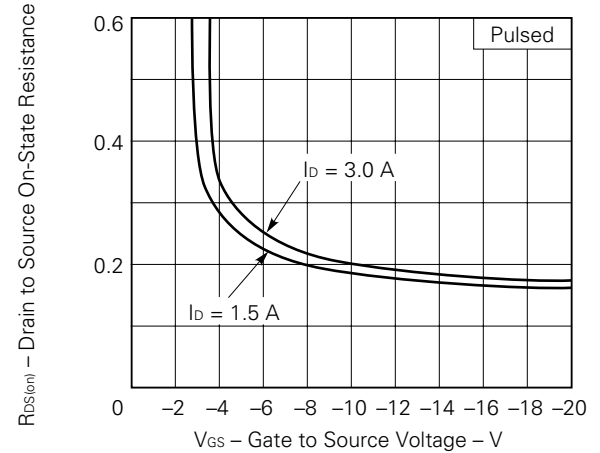
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



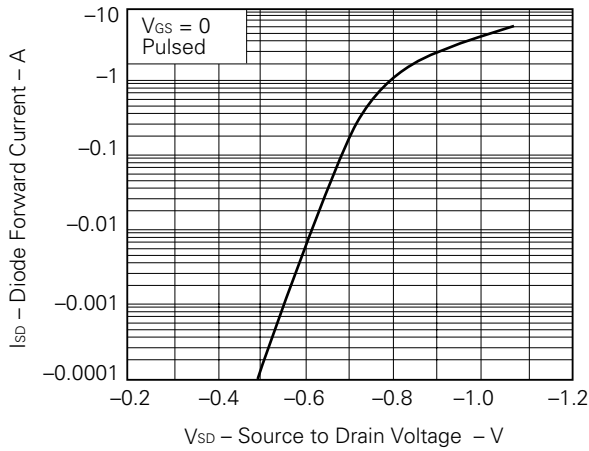
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



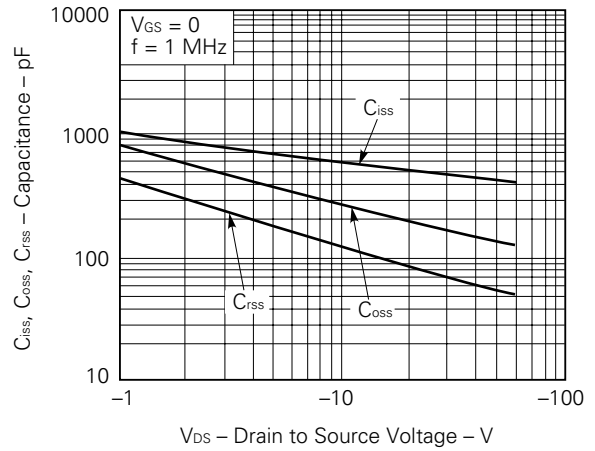
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



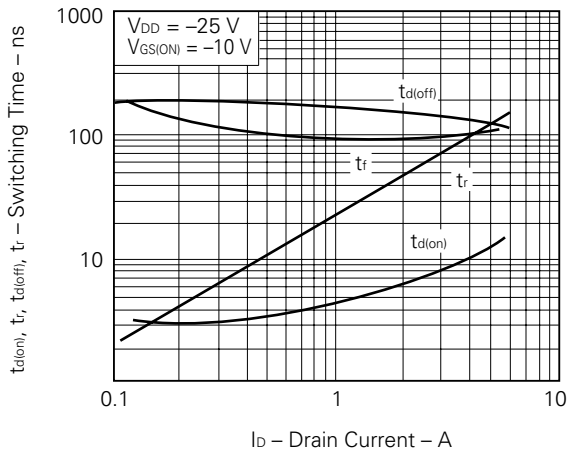
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



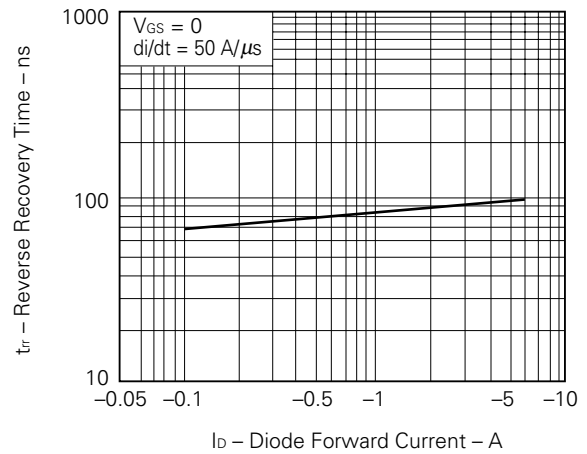
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



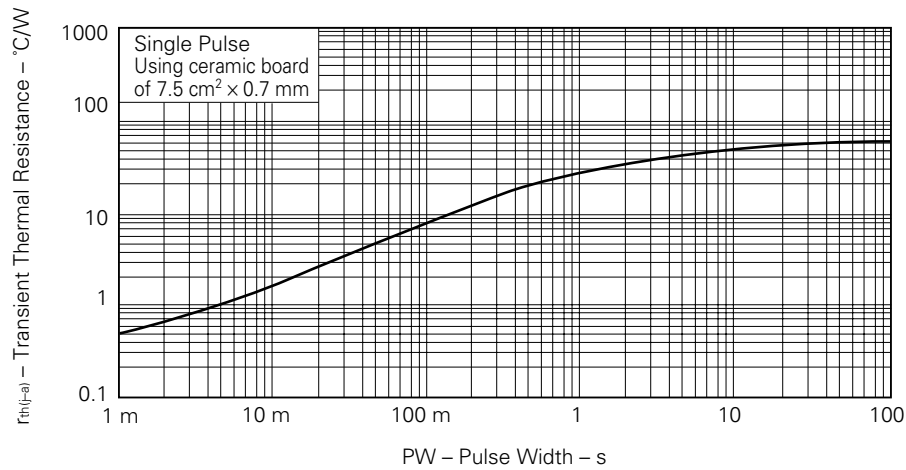
SWITCHING CHARACTERISTICS



REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



RELATED DOCUMENTS

Document Name	Document No.
Semiconductor Device Mounting Technology Manual	IEI-1207
NEC Semiconductor Device Reliability/Quality Control System	TEI-1202
Guide to Quality Assurance for Semiconductor Device	MEI-1202

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Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.